# Measurement of charge collection in p-type microstrip sensors with SCT128 chip

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Setup for measurements with SCT128 chip was built in Ljubljana:

- SCTA128VG chip
- drawings of test pcb from CERN (thanks to <u>Jan Kaplon</u>)
- VME module SEQSI (for clock, commands...)
- Tektronix digital scope for data acquisition
- Cambridge LabView software for chip control (thanks to <u>Dave Robinson</u>)
- data acquisition software (thanks to G. Kramberger)
- pitch adapters from Freiburg (thanks to Uli Parzefal)
- coincidence circuit made by Erik Margan
- <sup>90</sup>Sr source, photomultiplier, scintillator, power supplies....





#### Test PCB











Setup in the freezewr, temperature about -  $20^{\circ}$  C



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## SCTA128VG chip

- 128 channels
- charge sensitive front-end amplifier with about 20 ns peaking time
- sampled every 25 ns (40 MHz sampling clock)
- Gain = 26.5 mV/fC = 4.2  $\mu$ V/el measured with calibration signals from on-chip capacitors (~10 % accuracy)
- noise with detector connected ~ 800 el



#### Detectors

- p-type, FZ material, 300 µm thick miniature (~ 1 cm<sup>2</sup>) strip detectors
- strip pitch 80 µm
- n-in-p capacitively coupled
- polysilicon biased, p-sprayed
- designed by Liverpool produced by Micron



#### CV measurement, contact through bias ring



- detectors were irradiated with neutrons in the TRIGA reactor in Ljubljana
- 1 MeV equivalent fluences (same fluence steps as for Liverpool):
  - 5·10<sup>14</sup> n/cm<sup>2</sup>
  - 1.6·10<sup>15</sup> n/cm<sup>2</sup>
  - 3·10<sup>15</sup> n/cm<sup>2</sup>
- after irradiation detectors were annealed for 80 minutes at 60  $^\circ$  C
- measurements done in the freezer



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Measurements

- trigger: signals caused by electrons from <sup>90</sup>Sr source in scintillator in coincidence with 40 MHz clock edge
- spectrum of signals from strips (pedestals and common mode variations subtracted) fitted with convolution of Landau and Gauss functions
  - ➔ "Most Probable Value" of the Landau function (parameter p1 in the plot below) returned by the fit is the measure of collected charge



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Detector irradiated to 5.1014 n/cm<sup>2</sup>

- from CV: FDV ~ 600 V
- almost no kink can be seen in Charge vs. Voltage plot at about 600 V
- charge as high as before irradiation measrued at high voltage



Signal vs. Bias Voltage

- statistical error of points returned by the fit ~ 5%
- highest voltage limited by breakdown
- repeats of measurements are shown at two highest fluences :
  - ➔ reproducibility ~10%



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Comparison of spectra in which MP ~ 20 kel measured after different fluences (normalized to the equal number of clusters in histogram)

• signals at high voltage after irradiation as high as before irradiation



# Forward bias

different electric field + trapping → smaller signals



Signal vs. Fluence

- good agreement with Liverpool results
- with present cabling in ATLAS the highest voltage is 500 V
- higher voltage helps!



### Conclusions

- signals caused by fast electrons from <sup>90</sup>Sr source in p-type microstrip detectors were measured with SCT128 chip
- measurements were made up to very high bias voltages (max.2050 V)
- charge as high as before irradiation measured at sufficiently high voltage in detectors irradiated up to  $\Phi = 3.10^{15} \text{ n/cm}^2$
- good agreement with measurements from Liverpool

(Near) future work:

• repeat measurements with p-type strip detectors from Hamamatsu



Backup plots



Modul 0,  $\Phi_{eq}$  = 0 n/cm<sup>2</sup>, exposed to few Mrads of gammas



#### Signal to noise

• measurements for which MPV ~ 20000 el



Pulse shape

- signal mean vs. trigger delay, before irradiation
- Bias = 200 V

